

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination VERSIC ET AL.	
		Examiner Kimberly D. Nguyen	Art Unit 2876	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,951,596	10-2005	Green et al.	156/264
*	C	US-5,059,471	10-1991	McNally et al.	428/143
*	D	US-6,940,408	09-2005	Ferguson et al.	340/572.7
*	E	US-6,518,887	02-2003	Suzuki et al.	340/572.8
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Yoshihara et al (DE 19957111 A1), Semiconductor component, e.g. wafer of sensor..., 31 May 2000.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.